

**Search Notes**

Application/Control No.

10/625,209

Examiner

Mark A. Mais

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	310 316	3/18/2007	MAM
	319-322		
	328 395.1		
	395.21		
	395.4		
	395.41		
	395.42		
	431 437		
455	12.1 427		
	430		
SAME AS	ABOVE	9/19/2007	MAM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
370	316 328	9/19/2007	MAM
	431		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	3/18/2007	MAM
See Attached electronic Search	3/18/2007	MAM
See Attached electronic Search [updated]	9/19/2007	MAM
See Interference Search	9/19/2007	MAM